

# FDMA1027PT

## Dual P-Channel PowerTrench® MOSFET

-20 V, -3 A, 120 mΩ

### Features

- Max  $r_{DS(on)}$  = 120 mΩ at  $V_{GS} = -4.5$  V,  $I_D = -3.0$  A
- Max  $r_{DS(on)}$  = 160 mΩ at  $V_{GS} = -2.5$  V,  $I_D = -2.5$  A
- Max  $r_{DS(on)}$  = 240 mΩ at  $V_{GS} = -1.8$  V,  $I_D = -1.0$  A
- Low profile - 0.55 mm maximum - in the new package MicroFET 2x2 **Thin**
- RoHS Compliant



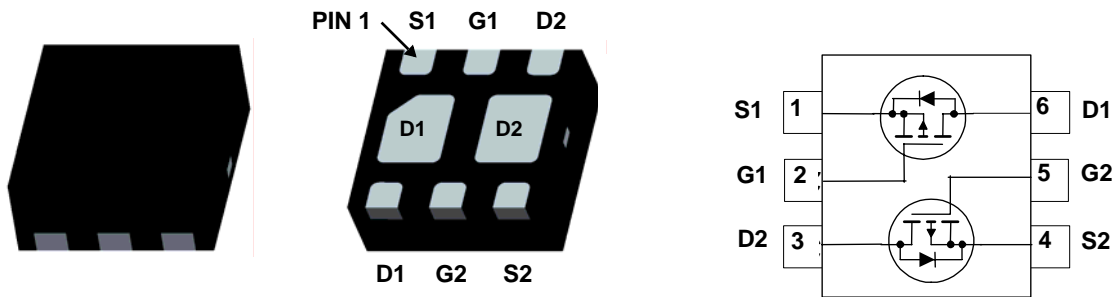
### General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connected in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 2x2 **Thin** package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.

### Applications

- Battery management
- Load switch
- Battery protection



MicroFET 2X2 Thin

### MOSFET Maximum Ratings $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain to Source Voltage	-20	V
$V_{GS}$	Gate to Source Voltage	±8	V
$I_D$	Drain Current -Continuous $T_A = 25$ °C (Note 1a)	-3	A
	-Pulsed	-6	
$P_D$	Power Dissipation for Single Operation $T_A = 25$ °C (Note 1a)	1.4	W
	Power Dissipation for Single Operation $T_A = 25$ °C (Note 1b)	0.7	
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	°C

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	86	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	173	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Dual Operation)		69	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Dual Operation)		151	

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
27	FDMA1027PT	MicroFET 2x2 <b>Thin</b>	7 "	8 mm	3000 units

## Electrical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Off Characteristics

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250\text{ }\mu\text{A}$ , $V_{GS} = 0\text{ V}$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$ , referenced to $25\text{ }^\circ\text{C}$		-12		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{ V}$ , $V_{GS} = 0\text{ V}$			-1	$\mu\text{A}$
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 8\text{ V}$ , $V_{DS} = 0\text{ V}$			$\pm 100$	nA

### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = -250\text{ }\mu\text{A}$	-0.4	-0.7	-1.3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\text{ }\mu\text{A}$ , referenced to $25\text{ }^\circ\text{C}$		2		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Drain to Source On Resistance	$V_{GS} = -4.5\text{ V}$ , $I_D = -3.0\text{ A}$		90	120	m $\Omega$
		$V_{GS} = -2.5\text{ V}$ , $I_D = -2.5\text{ A}$		120	160	
		$V_{GS} = -1.8\text{ V}$ , $I_D = -1.0\text{ A}$		172	240	
		$V_{GS} = -4.5\text{ V}$ , $I_D = -3.0\text{ A}$ , $T_J = 125\text{ }^\circ\text{C}$		118	160	
$I_{D(on)}$	On to State Drain Current	$V_{GS} = -4.5\text{ V}$ , $V_{DS} = -5\text{ V}$	-20			A
$g_{FS}$	Forward Transconductance	$V_{DS} = -5\text{ V}$ , $I_D = -3.0\text{ A}$		7		S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = -10\text{ V}$ , $V_{GS} = 0\text{ V}$ , $f = 1\text{ MHz}$		435		pF
$C_{oss}$	Output Capacitance			80		pF
$C_{rss}$	Reverse Transfer Capacitance			45		pF

### Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = -10\text{ V}$ , $I_D = -1.0\text{ A}$ $V_{GS} = -4.5\text{ V}$ , $R_{GEN} = 6\text{ }\Omega$		9	18	ns
$t_r$	Rise Time			11	19	ns
$t_{d(off)}$	Turn-Off Delay Time			15	27	ns
$t_f$	Fall Time			6	12	ns
$Q_g$	Total Gate Charge	$V_{DD} = -10\text{ V}$ , $I_D = -3.0\text{ A}$ $V_{GS} = -4.5\text{ V}$		4	6	nC
$Q_{gs}$	Gate to Source Gate Charge			0.8		nC
$Q_{gd}$	Gate to Drain "Miller" Charge			0.9		nC

### Drain-Source Diode Characteristics

$I_S$	Maximum continuous Drain-Source Diode Forward Current			-1.1	A
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{ V}$ , $I_S = -1.1\text{ A}$ (Note 2)	-0.8	-1.2	V
$t_{rr}$	Reverse Recovery Time	$I_F = -3.0\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$		17	ns
$Q_{rr}$	Reverse Recovery Charge			6	nC

#### Notes:

- $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a. 86  $^\circ\text{C}/\text{W}$  when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 173  $^\circ\text{C}/\text{W}$  when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300  $\mu\text{s}$ , Duty cycle < 2.0%.

**Typical Characteristics**  $T_J = 25\text{ }^\circ\text{C}$  unless otherwise noted

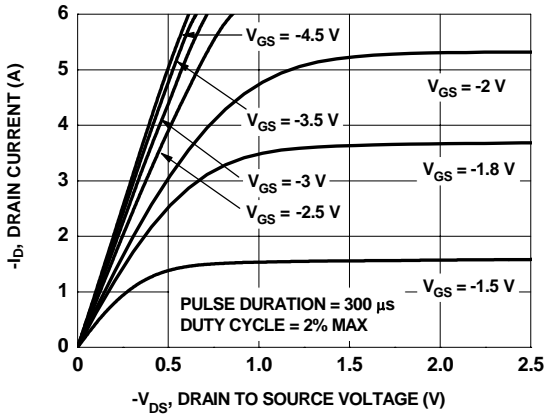


Figure 1. On Region Characteristics

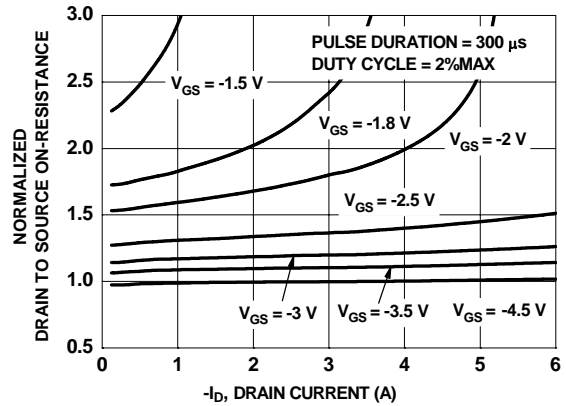


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

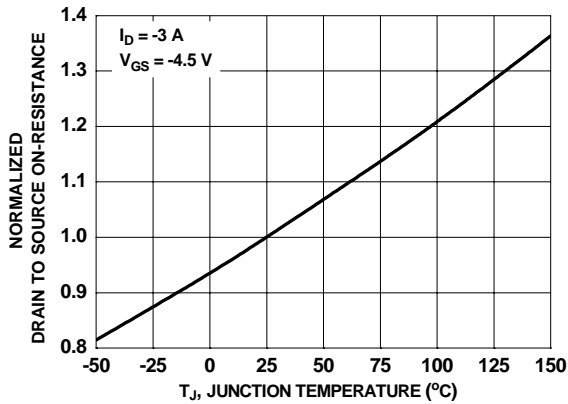


Figure 3. Normalized On Resistance vs Junction Temperature

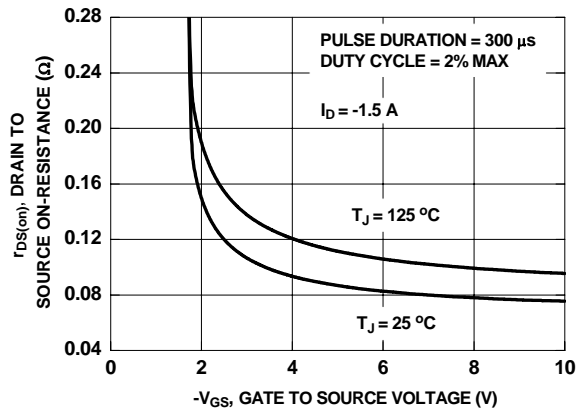


Figure 4. On-Resistance vs Gate to Source Voltage

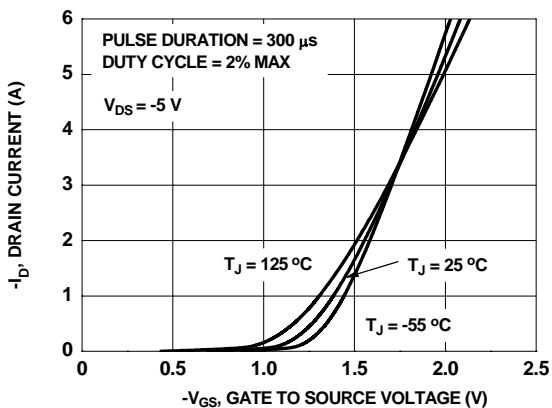


Figure 5. Transfer Characteristics

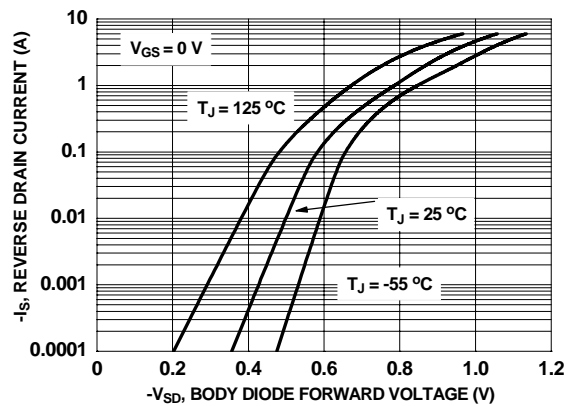
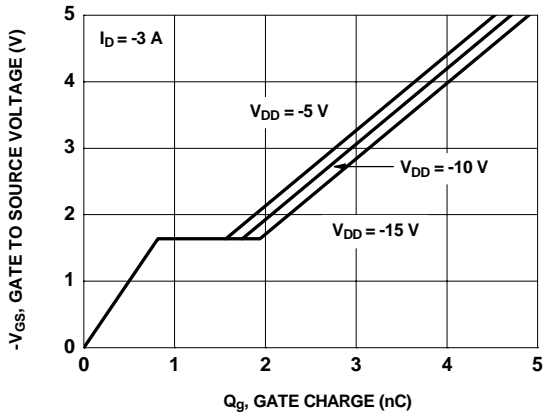
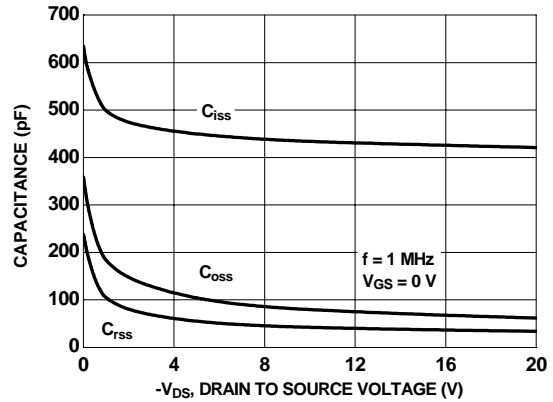


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

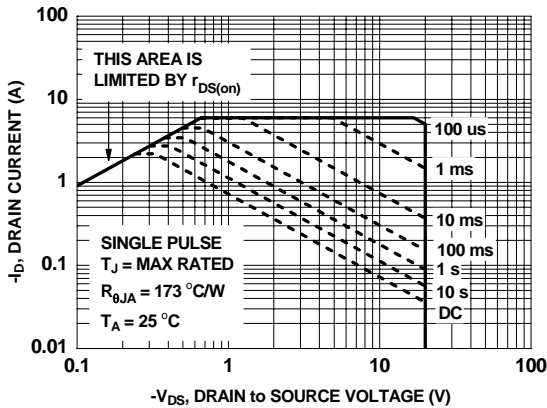
**Typical Characteristics**  $T_J = 25\text{ }^\circ\text{C}$  unless otherwise noted



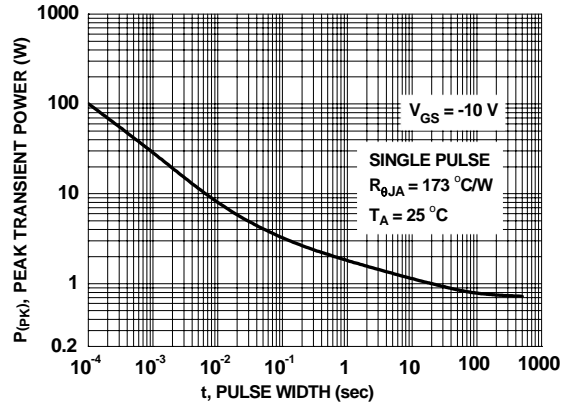
**Figure 7. Gate Charge Characteristics**



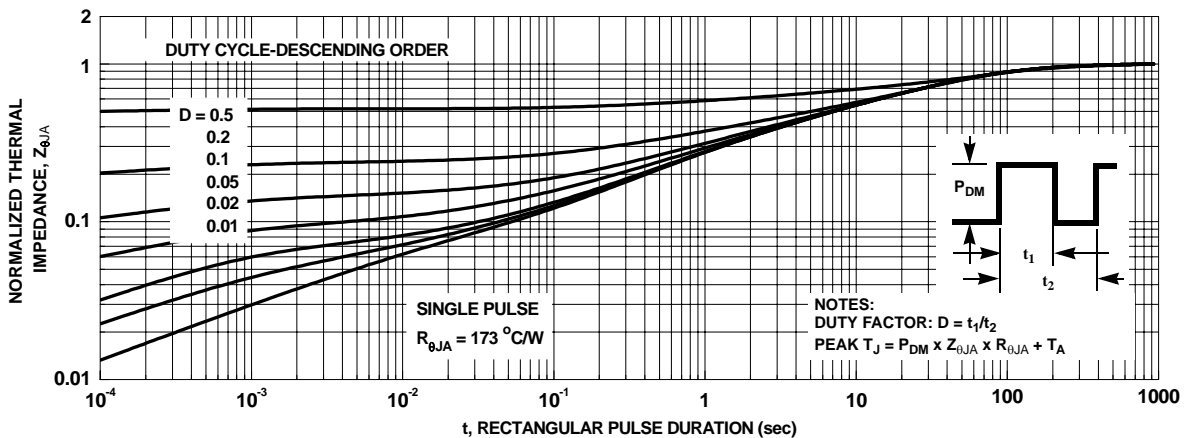
**Figure 8. Capacitance vs Drain to Source Voltage**



**Figure 9. Forward Bias Safe Operating Area**

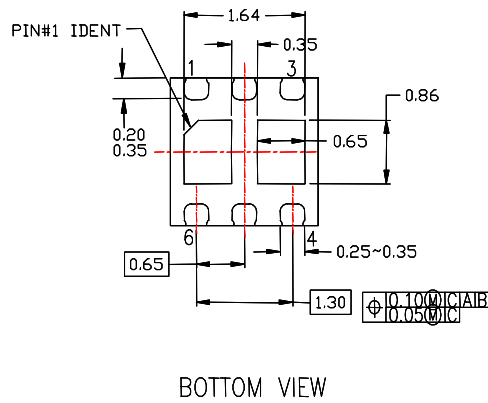
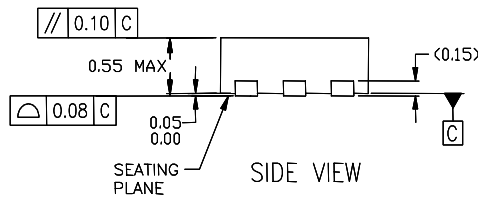
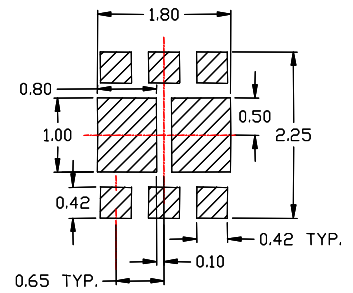
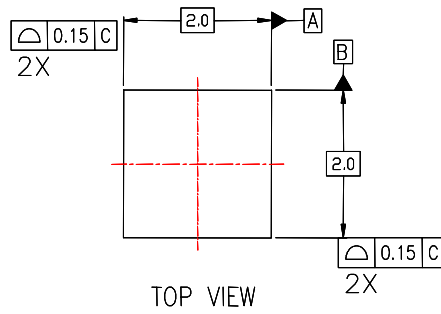


**Figure 10. Single Pulse Maximum Power Dissipation**



**Figure 11. Junction-to-Ambient Transient Thermal Response Curve**

## Dimensional Outline and Pad Layout







### NOTES:

- A. NON CONFORMS TO JEDEC REGISTRATION MO-288,
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994



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